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**Orlando et al.**

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(54) **SYSTEM AND METHOD FOR  
SPATIALLY-RESOLVED CHEMICAL  
ANALYSIS USING MICROPLASMA  
DESORPTION AND IONIZATION OF A  
SAMPLE**

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12, 2007, provisional application No. 61/107,886,  
filed on Oct. 23, 2008.

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**H01J 17/00** (2006.01)

**H01J 17/49** (2006.01)

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250/425; 250/281; 250/282

(58) **Field of Classification Search** ..... 250/423 F,  
250/423 R, 424, 425, 281, 282, 288  
See application file for complete search history.

(56) **References Cited**

**U.S. PATENT DOCUMENTS**

6,346,770 B1 \* 2/2002 Schoenbach et al. .... 313/491  
6,433,480 B1 \* 8/2002 Stark et al. .... 313/631  
6,624,583 B1 \* 9/2003 Coll et al. .... 315/111.71

6,703,784 B2 \* 3/2004 Vonallmen ..... 315/111.71  
6,762,407 B2 \* 7/2004 Kalinitchenko ..... 250/294  
6,818,193 B2 \* 11/2004 Christodoulatos et al. ... 423/210  
6,867,548 B2 3/2005 Eden et al.  
7,123,361 B1 \* 10/2006 Doughty ..... 356/316  
7,482,750 B2 \* 1/2009 Eden et al. .... 313/582  
7,709,814 B2 \* 5/2010 Waldfried et al. .... 250/492.2  
2007/0108910 A1 5/2007 Eden et al.

**OTHER PUBLICATIONS**

Miclea, Manuela; Kunze, Kerstin; Franzke, Joachim; and Niemax,  
Kay; "Microplasma Jet Mass Spectrometry of Halogenated Organic  
Compounds;" J. Anal. At. Spectrom.; 2004; 19; pp. 990-994.

\* cited by examiner

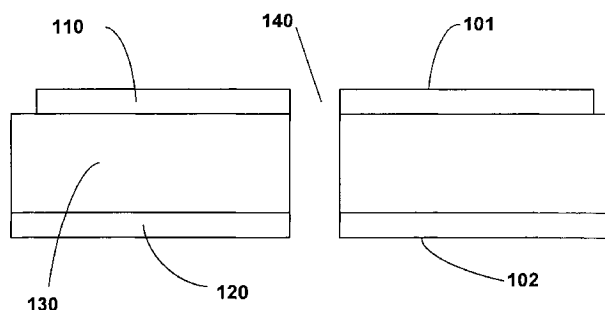
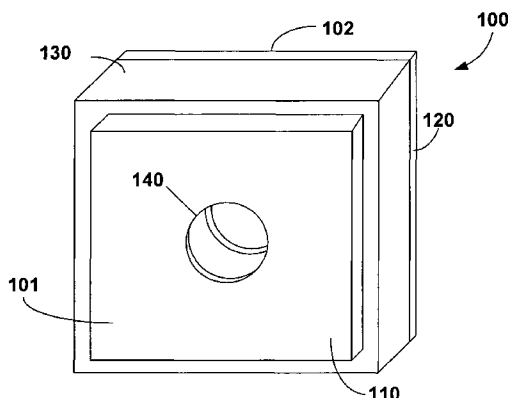
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(57) **ABSTRACT**

A method and system for desorbing and ionizing molecules from a sample for mass spectrometry using a microplasma device is disclosed. The system and method relies upon a microplasma device, or array of such devices, to partially ionize a gas to form a microplasma. The ionized gas can be a mixture of a noble gas, such as neon or argon, and hydrogen (H<sub>2</sub>). The ionized gas can form an effluent stream directed onto the surface of a sample to desorb molecules from the remainder of the sample. The desorbed molecules can be ionized by the effluent stream as they leave the surface of the sample. The ionization process can include: photoionization, penning ionization, chemical ionization (proton transfer), and electron impact ionization. The ionized particles from the sample can be directed to a mass spectrometer for analysis. This can produce spatially-resolved mass spectral data, and can be conducted concurrently with another imaging system, such as a microscope.

**30 Claims, 14 Drawing Sheets**



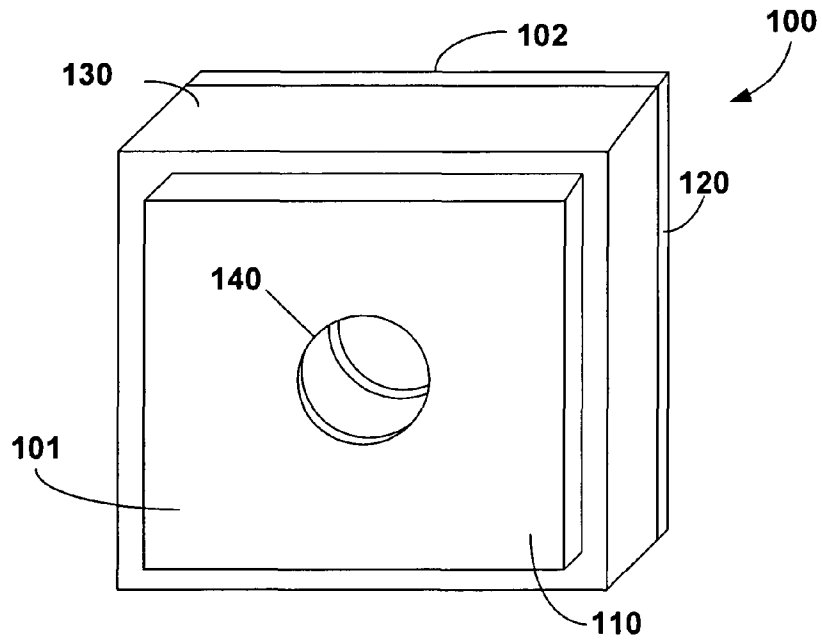


Fig. 1A

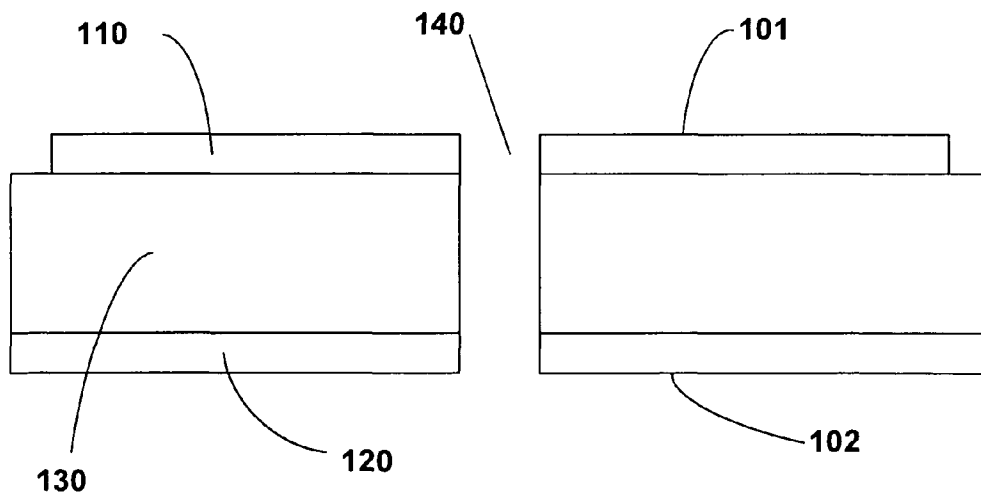


Fig. 1B

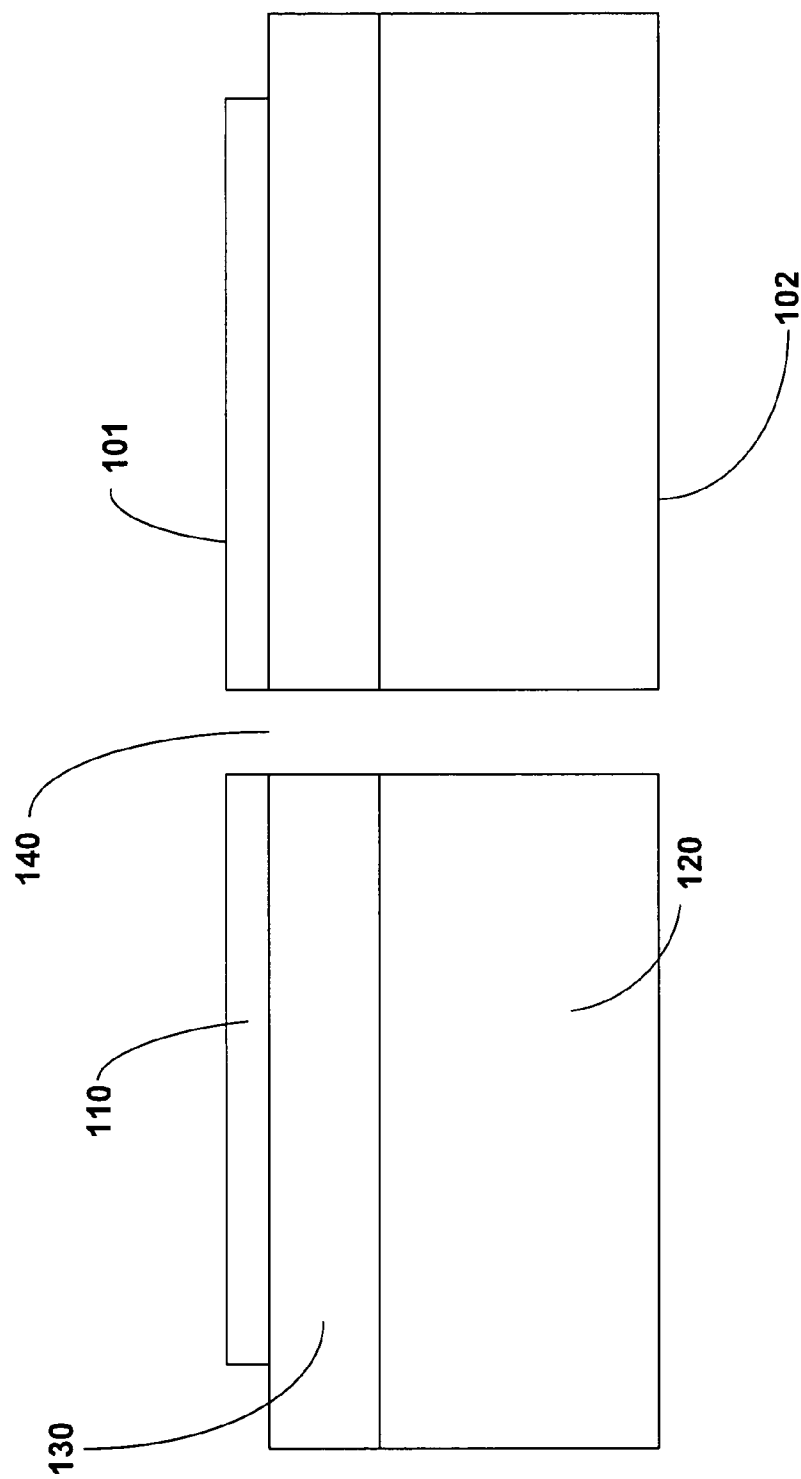
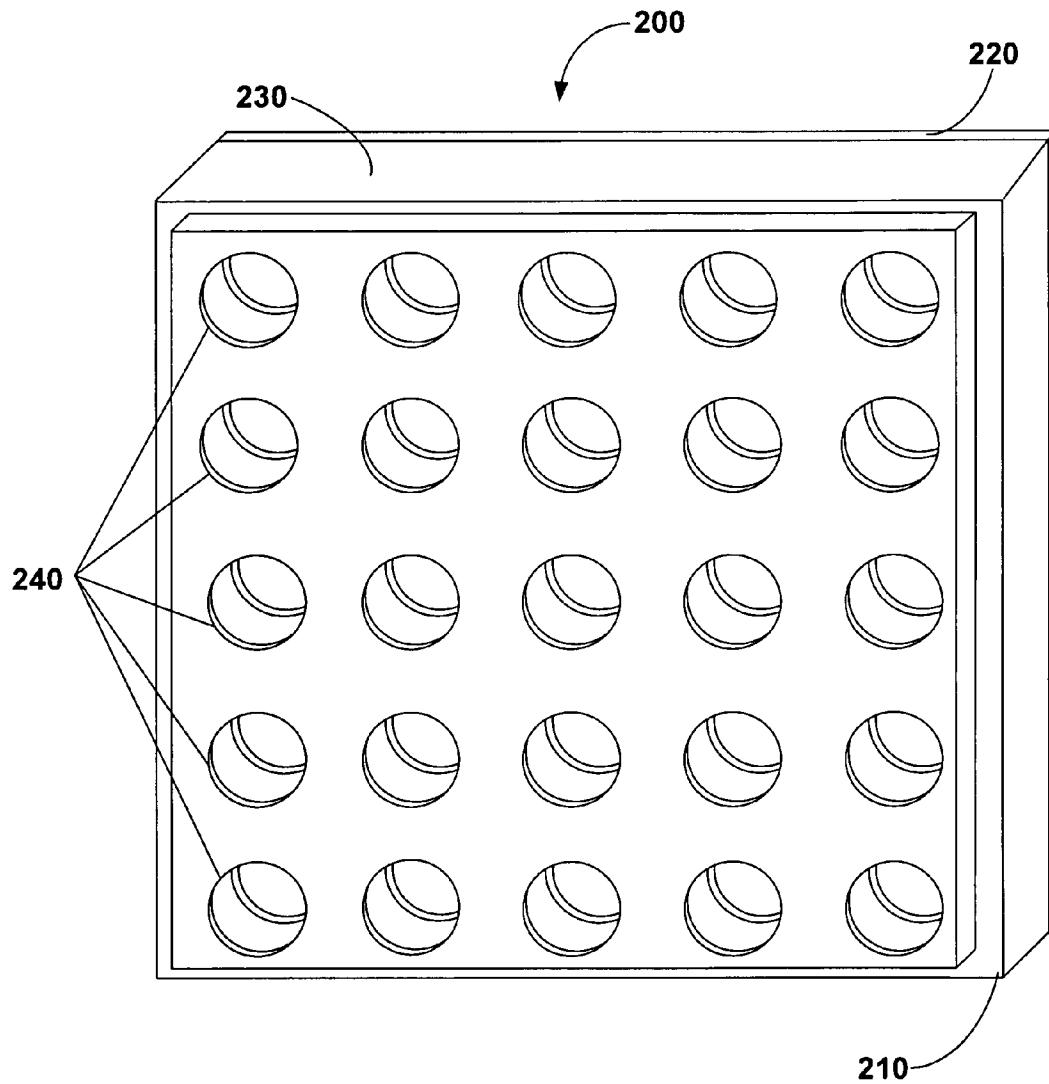


Fig. 1C

*Fig. 2*

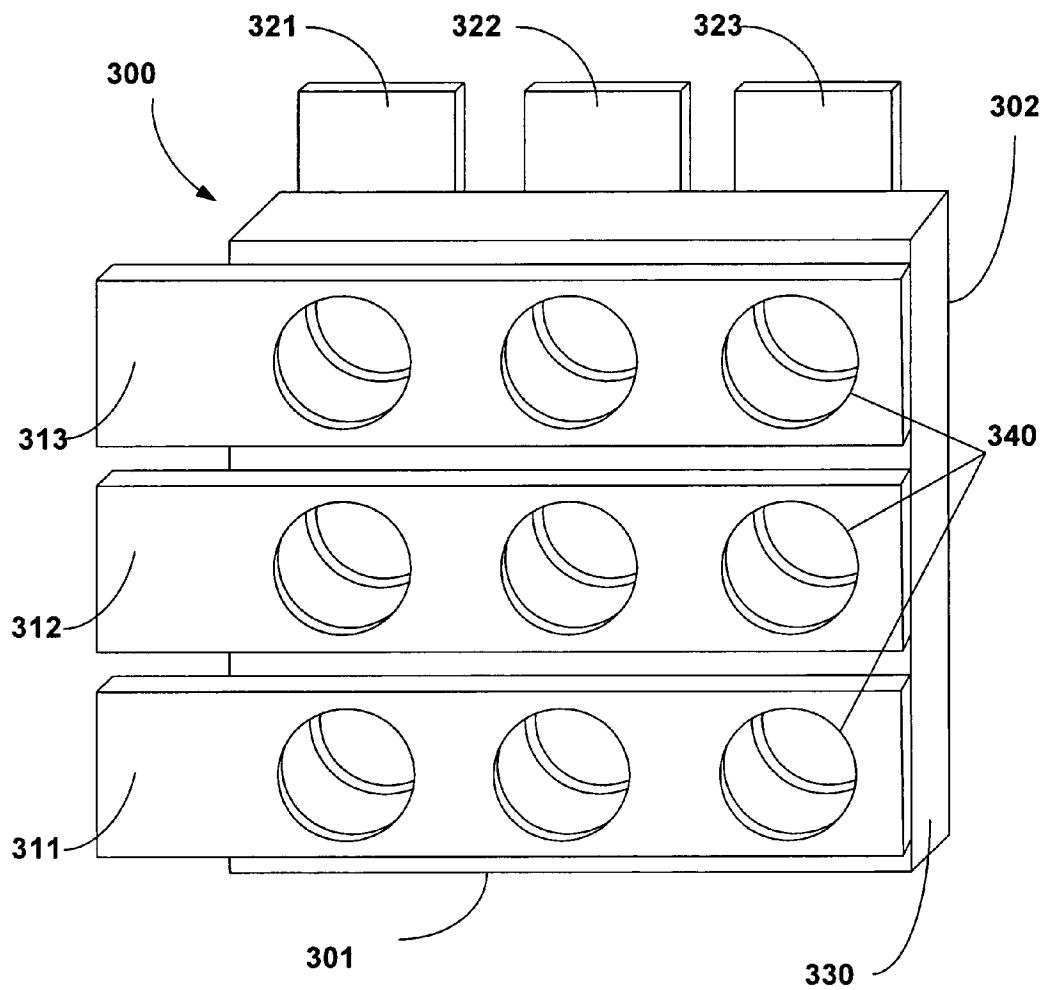


Fig. 3

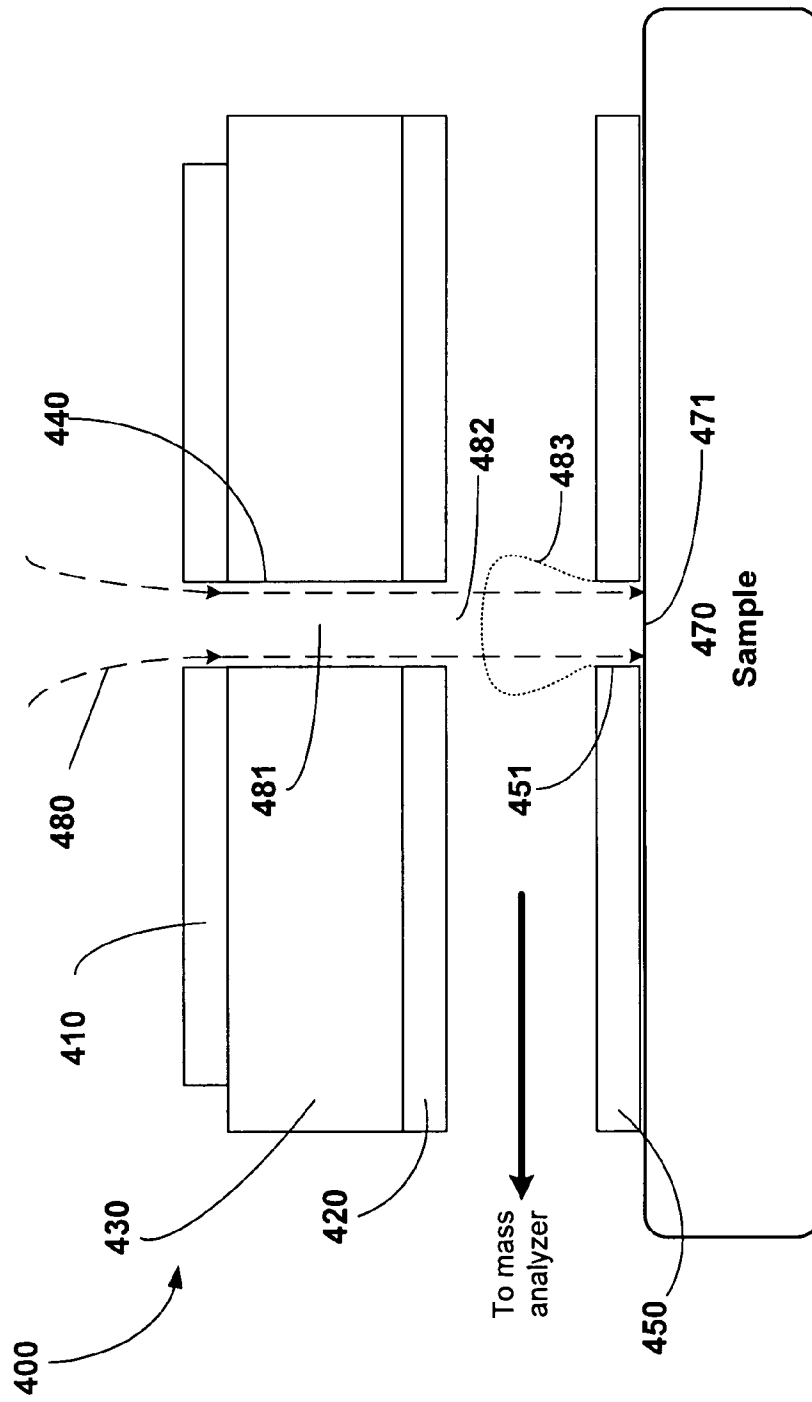


Fig. 4

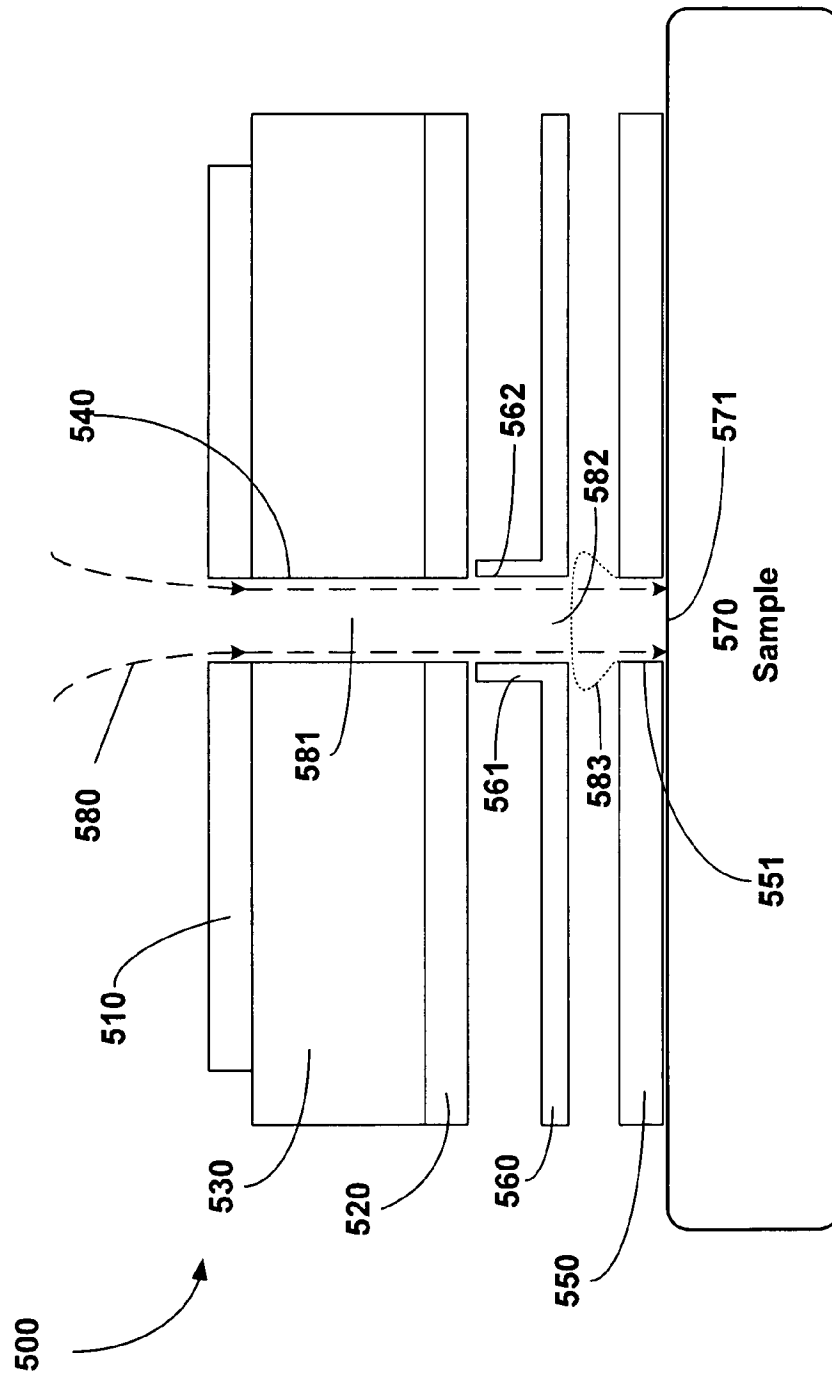
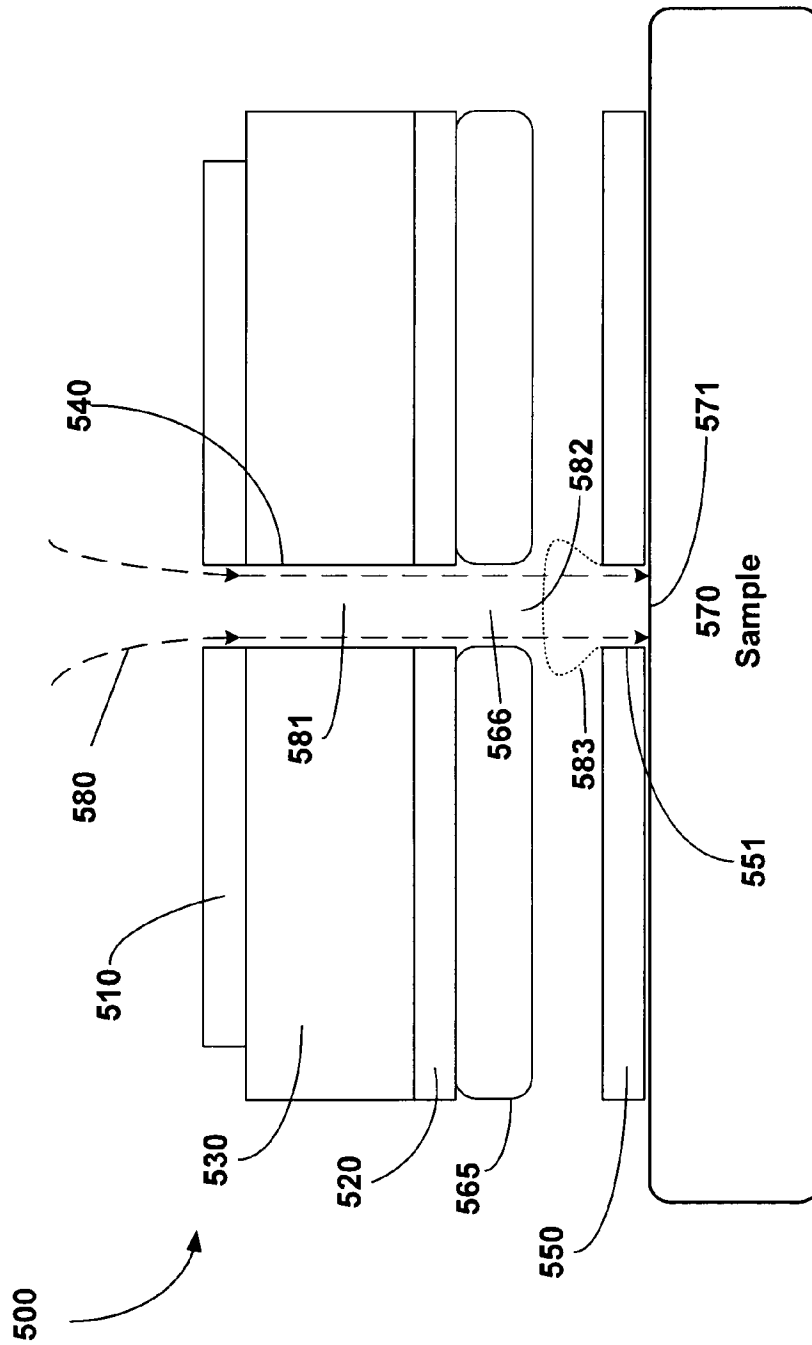


Fig. 5A



**Fig. 5B**



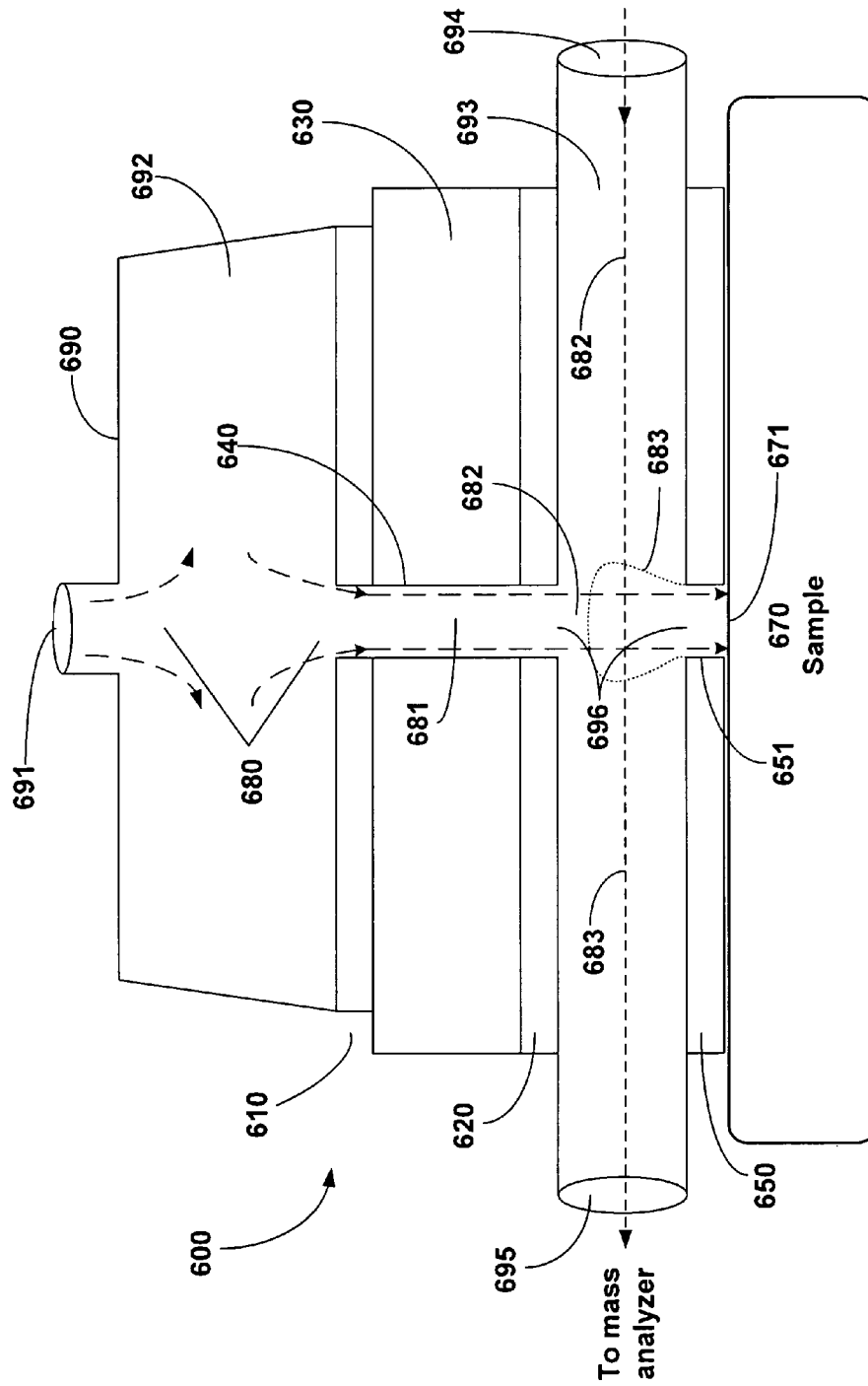


Fig. 6A

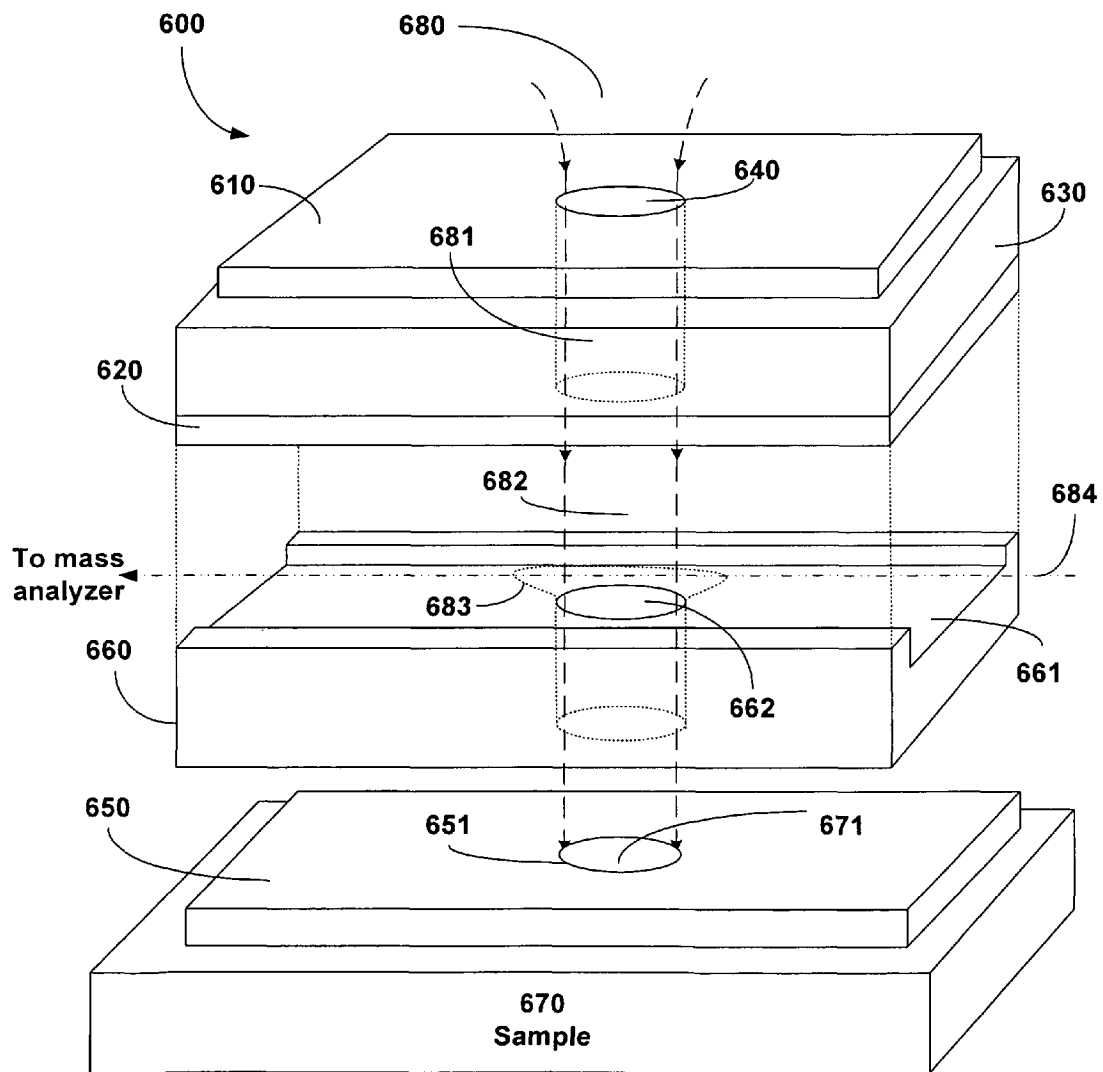
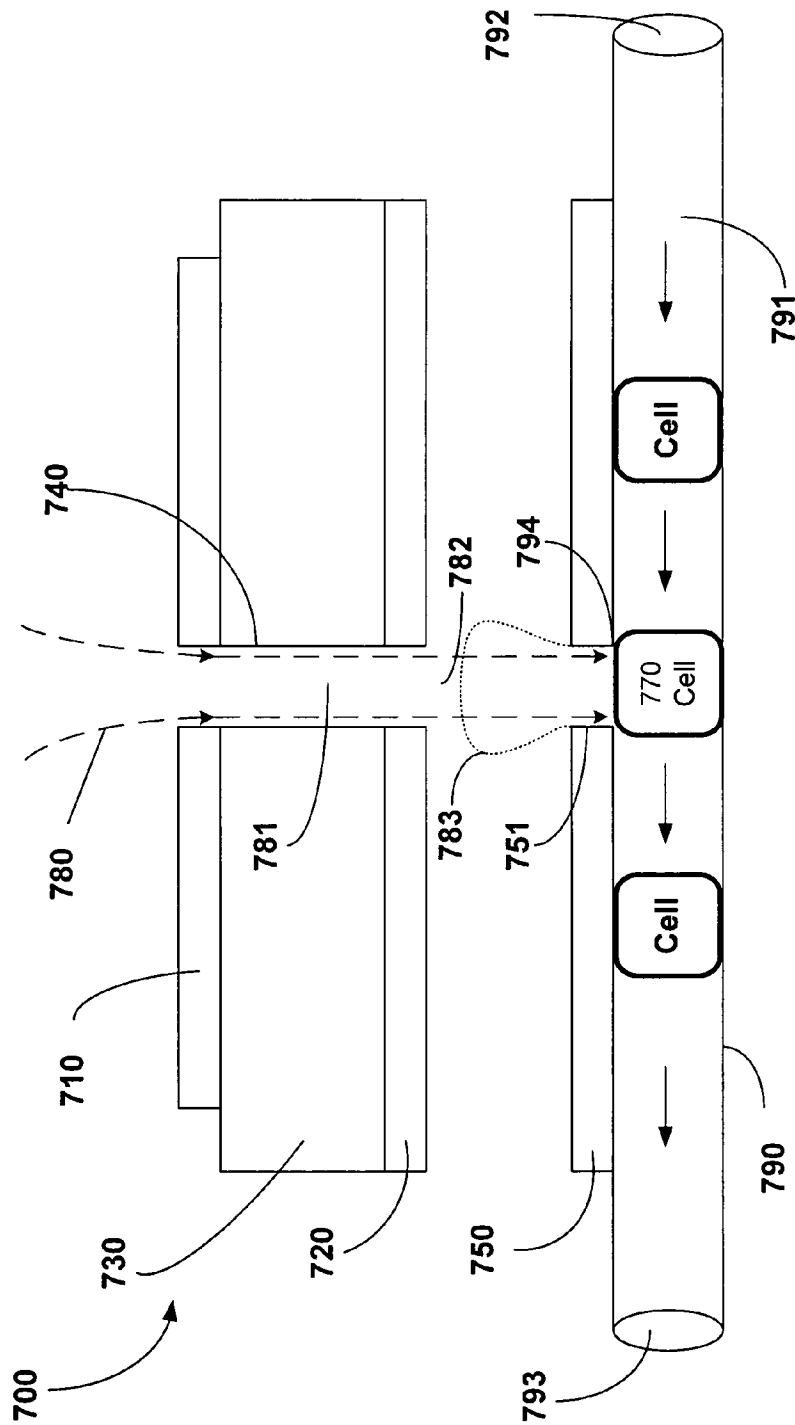
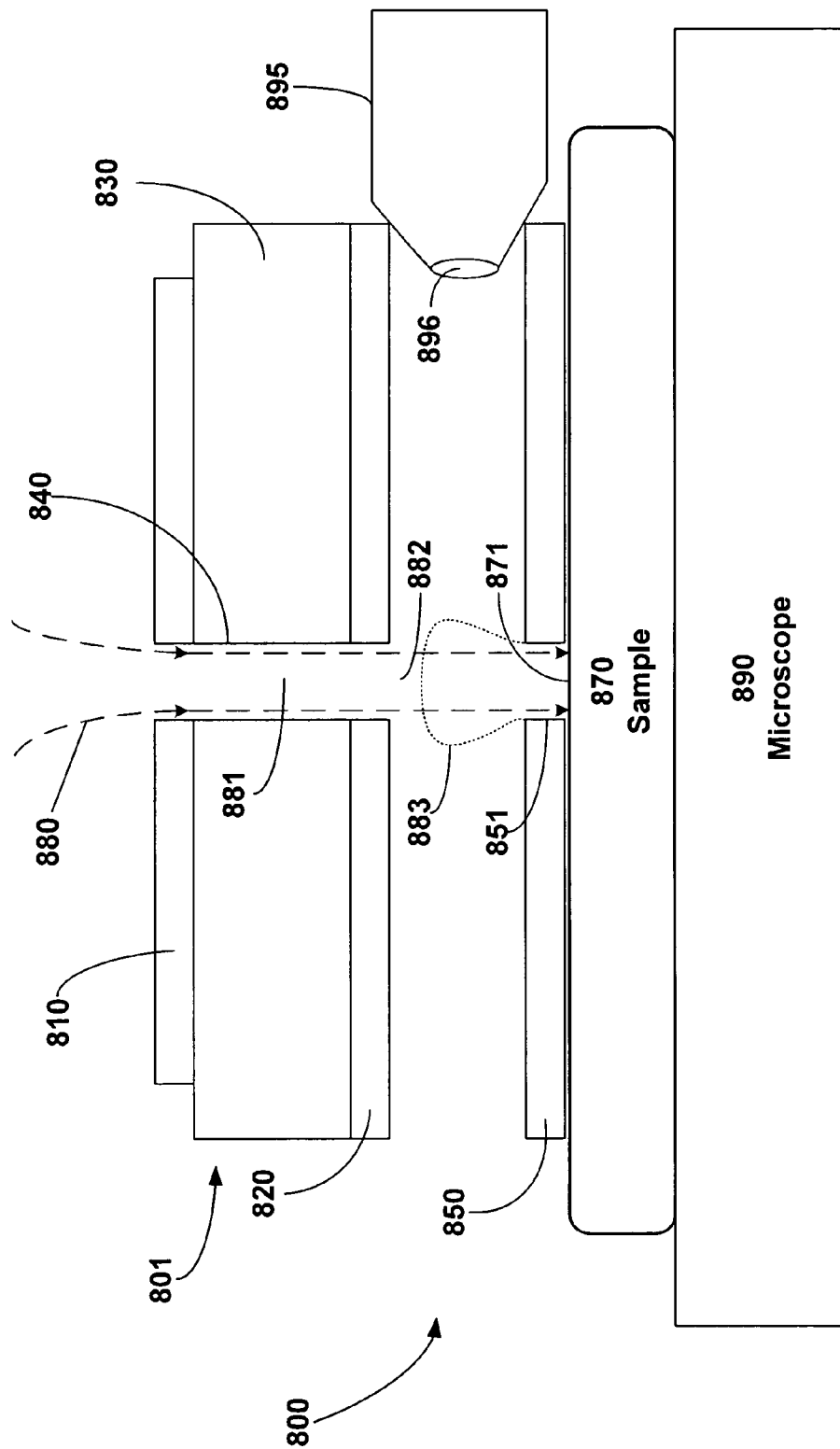


Fig. 6B



**Fig. 7**



**Fig. 8A**

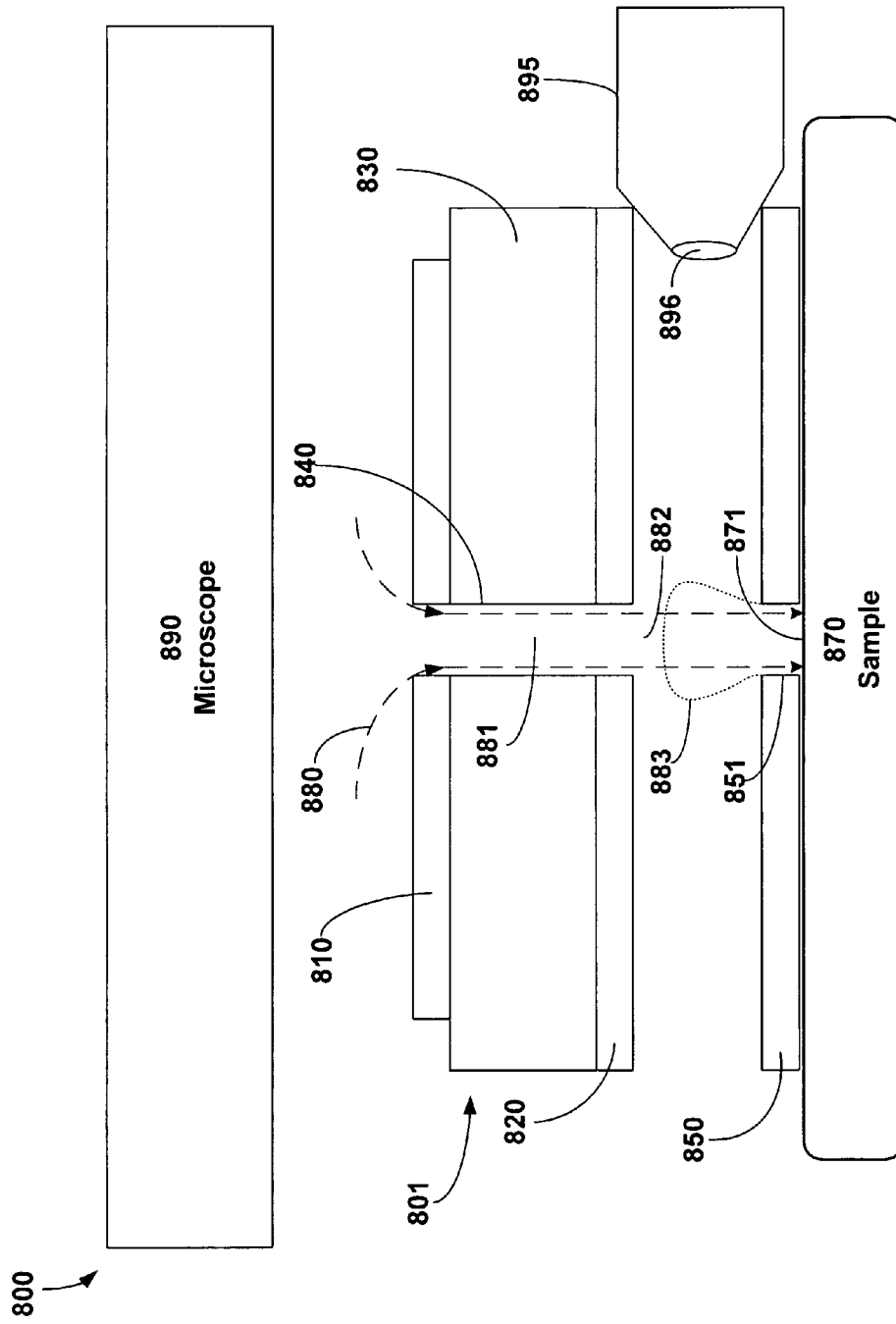


Fig. 8B

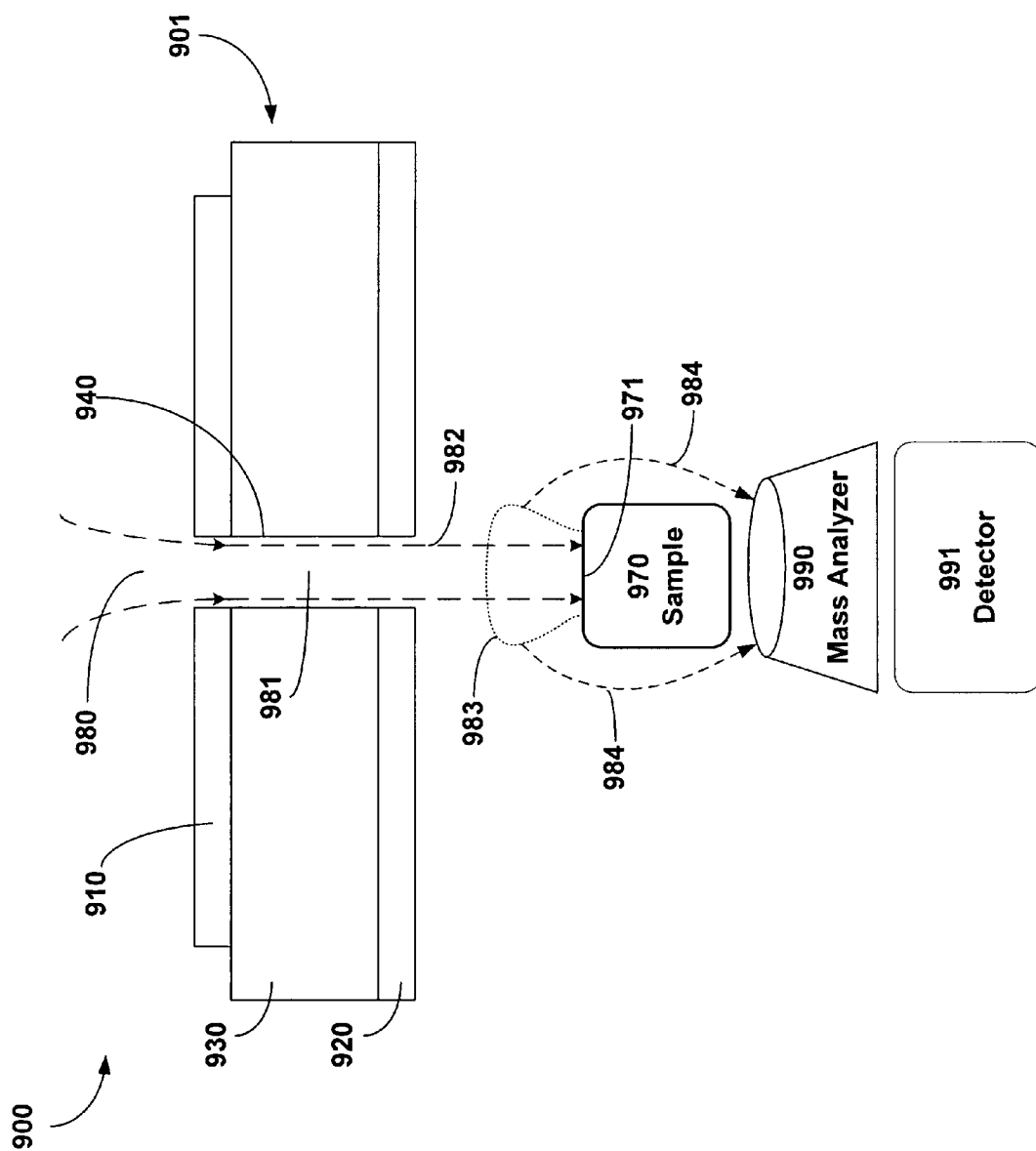


Fig. 9A

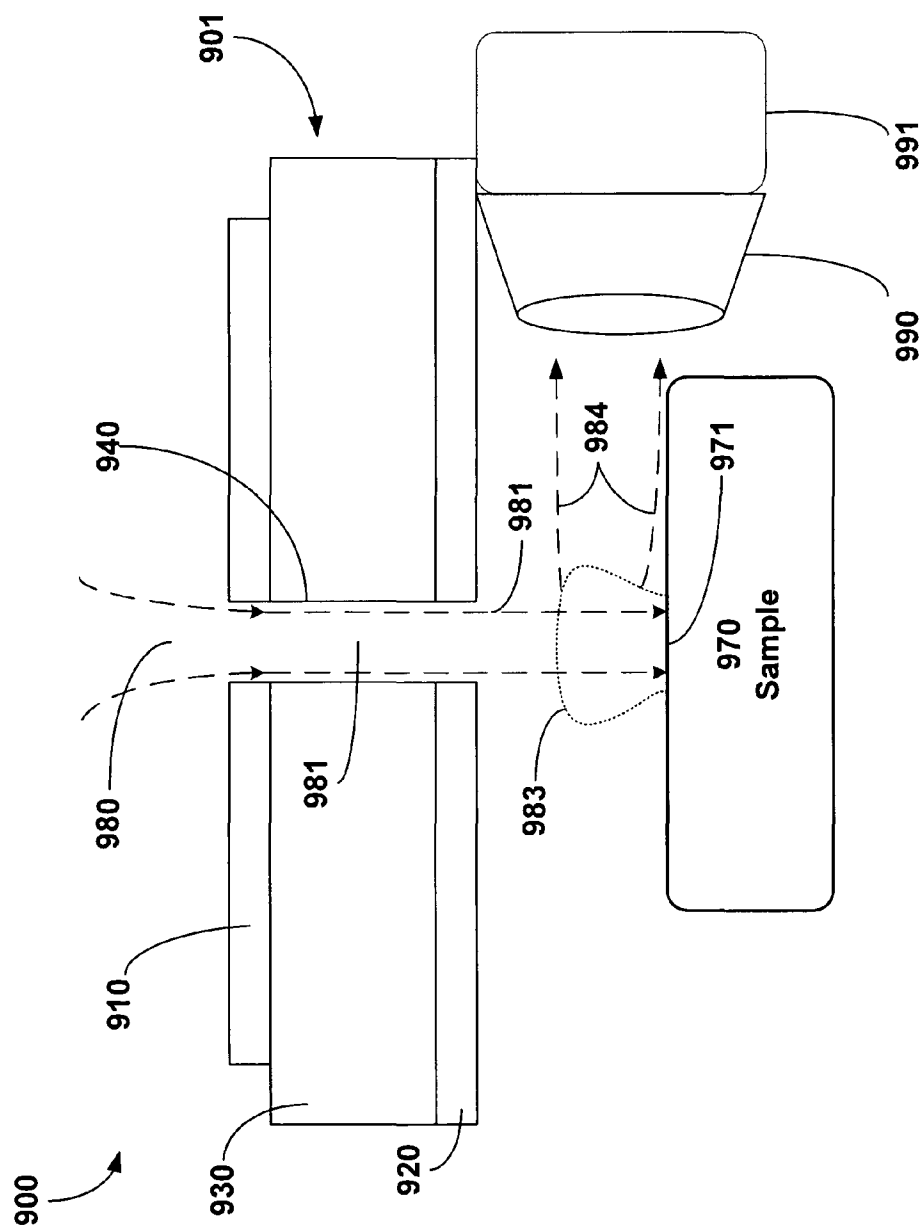


Fig. 9B

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# SYSTEM AND METHOD FOR SPATIALLY-RESOLVED CHEMICAL ANALYSIS USING MICROPLASMA DESORPTION AND IONIZATION OF A SAMPLE

## CROSS REFERENCE TO RELATED APPLICATIONS

This application claims benefit under 35 U.S.C. §119(e) of U.S. Provisional Patent Application Ser. No. 60/987,162, filed 12 Nov. 2007, and 61/107,886, filed 23 Oct. 2008, both of which applications are hereby incorporated by reference.

## BACKGROUND OF THE INVENTION

### 1. Field of the Invention

The present invention relates generally to microplasma-assisted desorption and ionization. In particular, the invention relates to a microplasma device serving as an ion source for a mass spectrometer.

### 2. Description of Related Art

Mass spectrometry is an analytical technique that identifies the chemical composition of a compound or sample based on the mass-to-charge ratio of charged particles. The technique requires a portion of the sample to be chemically fragmented and the fragmented segments to be ionized into charged particles. These particles are then passed into any type of mass spectrometer, which will determine their mass-to-charge ratio.

Three of the most common categories of mass spectrometers are known as time-of-flight mass analyzers, quadrupole mass analyzers, and ion trap mass analyzers. In each case, ions produced from the sample by the ion source are introduced using a variety of ion optics to guide the charged particles into the analyzer.

In a time-of-flight analyzer, the collection of ions are first accelerated through a region of known electric potential change. This gives each particle with the same charge the same amount of kinetic energy. The collection of accelerated ions are then allowed to travel through a region of zero electric field, and the time of their arrival at a detector at the end of this region is recorded. Particles with the same kinetic energy but different masses will travel through the "drift" region at different speeds, and thus reach the detector at different times. By this method the mass-to-charge ratio can be determined for each particle sensed by the detector.

A quadrupole mass analyzer operates by accepting the collection of ions into a region of oscillating electric field. By varying the parameters of this electric field the region can be made stable for a range of different mass-to-charge ratios. The quadrupole mass analyzer determines the mass-to-charge ratios for a variety of charged particles by quickly scanning through these stability parameters, keeping track of how many particles for each mass-to-charge ratio scanned through are detected.

An ion trap mass analyzer operates in a similar manner, but is capable of producing a field that is capable of trapping a number of particles with a range of mass-to-charge particles. The trap can modify the range of mass-to-charge ratios which are trapped, and thus by narrowing the stability region of operation certain mass-to-charge ratio particles can be released from the trap one by one and allowed to reach a detector outside, and the mass-to-charge ratio information recorded by the system. Other types of ion traps are capable of detecting the mass-to-charge ratio of charged particles in the trap without releasing them. This is accomplished by measur-

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ing the oscillation frequency of such particles in the trap by detecting the electromagnetic fields they produce, and analyzing the resulting data.

The use of electron, ion, and laser beams as an ion source for mass spectrometry-based imaging of surface and tissues is well known. Two popular approaches currently used are matrix assisted laser desorption ionization (MALDI) and secondary ion mass spectrometry (SIMS). These techniques are limited to monitoring the desorbed ion yields under high vacuum conditions and have been used to image semiconductor surfaces, insulators, polymers, tissues, and histological samples. Most MALDI and laser desorption/ionization based mass spectrometry approaches, however, are not effective under ambient temperature and pressure conditions. Some approaches such as desorption electrospray ionization (DESI), direct analysis in real time (DART), and radiofrequency plasma assisted desorption ionization (PADI) have been successfully used under ambient conditions. The spatial resolution of these approaches, however, is limited to the mm scale due to limitations inherent in the technology, and their reliance upon detecting ion signals produced as a result of surface or above surface interactions.

Therefore, there remains a need for an ion source capable of operating under ambient conditions which can be used to analyze condensed-phase targets such as liquids and surfaces with improved spatial resolution. The embodiments of the invention described below meet this need.

## BRIEF SUMMARY OF THE INVENTION

Embodiments of the present invention are directed to a method and system for desorption and ionization of a sample for analysis via mass spectrometry using a microplasma device. Embodiments of the present invention rely upon a microplasma device, or an array of such devices, to partially ionize a gas to form a plasma. The ionized gas can be any pure gas or mixture of gasses, including air, argon, helium, neon. The addition of hydrogen ( $H_2$ ) to the rare gas plasma can produce high energy vacuum ultraviolet photons, which can aid in the desorption/ionization process. The gas effluent stream from the plasma, containing electrons, photons, ions, and metastable particles can be directed onto the surface of a sample to desorb and remove molecules from the sample. These desorbed molecules can be ionized by the plasma effluent as they leave the surface of the sample in the path of the effluent stream. The ionization process can include: electron impact ionization, photo-ionization, penning ionization, and chemical ionization (proton transfer). The ionized particles from the sample can be directed to a mass spectrometer for analysis.

The ionization attained by embodiments of the present invention can occur under ambient temperature and pressure conditions. The ionization achieved by the embodiments of the present invention is preferably primarily a non-thermal process, therefore, thermal fragmentation and damage to the sample is minimized or eliminated. The addition of hydrogen into the gas mixture increases the proton transfer probability and also produces Lyman- $\alpha$  photons. These photons can lead to further desorption and photo-ionization.

Embodiments of the present invention can be employed to ionize a wide variety of solid surfaces, including skin or cell cultures, or liquid samples. Embodiments of the present invention can be applied to mass spectrometry for surface analysis, proteomics, metabolomics, glycomics, cancer research, and studies of drug discovery and immune response.

Embodiments of the present invention can pair microscopy with mass spectrometry. A microplasma device can be dis-



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posed inline with a microscope. The microscope and sample can translate relative the microplasma device to position a desired area of the sample in the path of the effluent plume. In this manner, a specific area of a sample can be selected for analysis by mass spectrometry.

In an exemplary embodiment of the invention, a method for analyzing a sample using a microplasma device and a mass spectrometer comprises generating a field by exciting a first electrode and a second electrode separated by a dielectric element and injecting a gas through a first aperture to form a plasma, the first aperture traversing the first electrode, the second electrode, and the dielectric. The method further comprises directing an effluent stream from the first aperture onto a target surface of the sample and desorbing and ionizing molecules from the target surface using the effluent stream. The method additionally comprises deflecting the paths of the ionized molecules to a mass analyzer and determining the composition of the molecules

In an exemplary embodiment of the invention, the method for comprise an imaging mass spectrometry system comprises an ion source comprising a first electrode, a second electrode, a dielectric element disposed between the first and second electrodes, and a first aperture traversing the first electrode, second electrode, and dielectric element. The system further comprises a mass analyzer and a device for detecting charged particles.

In an exemplary embodiment of the invention, an ion source for an imaging mass spectrometry system, the ion source comprises a first electrode, a second electrode, and a dielectric element disposed between the electrodes. The ion source further comprises a first aperture traversing the first electrode, second electrode, and dielectric element, wherein an excitation of the first and second electrode transforms a gas flowing through the first aperture into a plasma, the first aperture adapted to direct an effluent stream of the plasma onto the surface of a sample to desorb molecules from the surface.

The Detailed Description and accompanying Drawings further describe these and other exemplary embodiments of a system and method for spatially-resolved chemical analysis using microplasma desorption and ionization of a sample.

### BRIEF DESCRIPTION OF THE FIGURES

FIG. 1A illustrates an exemplary embodiment of a microplasma device.

FIG. 1B illustrates a cross sectional view of an exemplary embodiment of microplasma device.

FIG. 1C illustrates a cross sectional view of an exemplary embodiment of the composition of a microplasma device.

FIG. 2 illustrates an exemplary embodiment of a microplasma device array.

FIG. 3 illustrates an exemplary embodiment of the array having separately addressable electrodes.

FIG. 4 illustrates a cross sectional view of an exemplary embodiment of a microplasma device in relation to a sample surface.

FIG. 5A illustrates a cross sectional view of an exemplary embodiment of a microplasma device with a guide electrode.

FIG. 5B illustrates a cross sectional view of an exemplary embodiment of a microplasma device with a solenoid.

FIG. 6A illustrates a cross sectional view of an exemplary embodiment of a sealed microplasma device.

FIG. 6B illustrates an exploded perspective view of an exemplary embodiment of a sealed microplasma device with a gas transport channel.

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FIG. 7 illustrates a cross sectional view of an exemplary embodiment of a microplasma device for use with a microfluidic sample.

FIG. 8A illustrates a cross sectional view of an exemplary embodiment of a mass spectrometry analysis system.

FIG. 8B illustrates a cross sectional view of alternative orientation of an exemplary embodiment of a mass spectrometry analysis system.

FIG. 9A illustrates a cross sectional view of an exemplary embodiment of a mass spectrometer comprising a microplasma ion source.

FIG. 9B illustrates an exemplary embodiment of an orthogonal orientation of an imaging mass spectrometry system comprising a microplasma ion source.

### DETAILED DESCRIPTION OF PREFERRED EMBODIMENTS

Referring now in detail to the drawing figures, wherein like reference numerals represent like parts throughout the several views, FIG. 1A illustrates a frontal perspective view of an exemplary embodiment of a microplasma device. In all of the Figures, the microplasma device(s) and features thereof are not illustrated to scale. The Figures are intended to clearly illustrate all of the elements and their functional relationships, rather than actual relative proportions. The microplasma device **100** can comprise a first electrode **110** and a second electrode **120**. The first and second electrodes, **110** and **120** can be separated by a dielectric **130**. The microplasma device **100** can comprise a first side **101** and a second side **102**.

The microplasma device **100** can further include an aperture **140**. The aperture **140** can traverse the width of the microplasma device **100**, forming a cylindrical channel through the first electrode **110**, dielectric **130**, and second electrode **120**. The cross-section of aperture **140** is preferably circular.

The microplasma device **100** can have a thickness of 10-1000  $\mu\text{m}$ . The electrodes **110** and **120** can each have a thickness of 100 nm-1000  $\mu\text{m}$ . The diameter of the cross-section of the aperture **140** can be 10-1000  $\mu\text{m}$ . In a preferred embodiment, the thickness of the microplasma device **100** can be 10-2000  $\mu\text{m}$ , the thickness of the electrodes **110** and **120** can be 200 nm-1000  $\mu\text{m}$ , and the diameter of the aperture **140** can be 10  $\mu\text{m}$ -300  $\mu\text{m}$ . The first electrode **101** can have a length and width less than that of the dielectric **130**. This can reduce arcing between the electrodes **110** and **120** along the edges of the device **100** and formation of plasma at the edges as well. In other contemplated embodiments, the first electrode **110** can have the same length and width as the dielectric **130** and the second electrode **120** can have a smaller length and width than the dielectric **130**. In further contemplated embodiments, insulation can be applied to the edges of electrode **110** and **120**, enabling both electrodes **110** and **120** to have a width and length substantially equal to the dielectric **130**. Additionally, it is contemplated that the first electrode **110** and the second electrode **120** can have a smaller length and width than the dielectric **130**.

The electrodes **110** and **120** can be composed of a metal such as molybdenum or nickel. The dielectric can be composed of any suitable insulating material, such as silicon dioxide or polyamide.

The microplasma device **100** can generate a plasma by passing a gas through the aperture **140** while the electrodes **110** and **120** are excited by, for example applied AC or DC voltage, in either continuous or pulsed mode. In an exemplary embodiment, a gas can be injected through the aperture **140** from the first side **110** to the second side **120**. The electrodes

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110 and 120 can be excited by DC, radio-frequency, AC or a pulsed voltage. If the field strength within the aperture 140 exceeds a threshold value, the gas passing through the aperture 140 can become partially ionized and form a low temperature plasma.

FIG. 1B illustrates a cross sectional view of an exemplary embodiment of a microplasma device 100. The dielectric 130 can be disposed between electrodes 110 and 120. The aperture 140 can traverse the entire thickness of the microplasma device 100. The first side 101 as illustrated is disposed at the top of the microplasma device 100 and the second side 102 is disposed at the bottom.

FIG. 1C illustrates a cross sectional view of an exemplary embodiment of the composition of a microplasma device 100. The dielectric 130 can be disposed between electrodes 110 and 120. The aperture 140 can traverse the entire thickness of the microplasma device 100. The first side 101 as illustrated is disposed at the top of the microplasma device 100 and the second side 102 is disposed at the bottom.

The second electrode 120 can be composed of a semiconductor or a conductor. For example, but not limitation, the second electrode can be composed of silicon (Si), nickel (Ni), or molybdenum (Mo). The dielectric 130 can be grown or deposited on the surface of the second electrode 120. For example, but not limitation, the dielectric 130 can be composed of silicon dioxide, mica, or polyamide. The first electrode 110 can be deposited on the surface of the dielectric 130. For example, but not limitation, the dielectric 130 can be composed of molybdenum (Mo). In other contemplated embodiments, the first electrode 110 can be composed of a semiconductor and the second electrode can be composed of a metal. In further contemplated embodiments, the electrodes 110 and 120 can both be composed of a metal or a semiconductor.

FIG. 2 illustrates an exemplary embodiment of a microplasma device array 200. The array 200 can be composed of a plurality of microplasma devices 100 as described above. The microplasma devices 100 can be integrally formed or coupled together to form the array 200.

FIG. 2 illustrates an embodiment wherein the array 200 can comprise 25 integrally formed microplasma devices 100. In other contemplated embodiments, the array 200 can comprise a different number of microplasma devices 100.

The array 200 can comprise a first electrode 210 and a second electrode 220. A dielectric 230 can be disposed between the electrodes 210 and 220. The array 200 can further comprise a plurality of apertures 240. In the illustrated embodiment, the array 200 comprises 25 apertures 240. The electrodes 210 and 220, the dielectric 230, and the apertures 240 can be substantially similar to the corresponding elements described above with regard to FIGS. 1A and 1B.

FIG. 3 illustrates an exemplary embodiment of the array having separately addressable electrodes, which produce separately addressable plasmas. The array 300 can comprise a first front electrode 311, a second front electrode 312, and a third front electrode 313 disposed in parallel on the first side 301 of the array 300. The electrodes 311, 312, and 313 can traverse the width of a dielectric element 330. The array 300 can further comprise a first back electrode 321, a second back electrode 322, and a third back electrode 323 disposed in parallel on the second side 302 of the array. The electrodes 321, 322, and 323 can traverse the width of the dielectric element 330. The electrodes 311, 312, and 313 can be oriented parallel or orthogonal to electrodes 321, 322, and 323. In the illustrated example, the relative orientation is orthogonal.

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The array 300 can comprise a plurality of apertures 340. The apertures traverse the thickness of the electrodes 311-313 and 321-323 and the dielectric 330. The apertures 340 can be substantially similar to the aperture 140 and 240 discussed above. FIG. 3 illustrates nine apertures 340. In other contemplated embodiments, other desired numbers of apertures can be employed.

The front electrodes 311, 312, 313 are preferably electrically isolated from each other. Similarly, the back electrodes 321, 322, and 323 are preferably electrically isolated from each other. Each of the electrodes 311-313 and 321-323 can be independently excited. For example, electrodes 312 and 322 can be excited while electrodes 311, 313, 321, and 323 are not excited. By selectively exciting certain electrodes, a magnetic and electric field can be generated in a desired aperture. For example, if electrode 313 and electrode 323 are excited, a field can be generated in the aperture in the upper right corner of the array 300.

By selectively generating a field in the apertures 340 in the array 300, desired portions of a sample surface can be ionized. Placing the array 300 above a sample surface, the area of the surface ionized by an effluent plume can be selected by exciting particular electrodes. This provides spatial mapping of the surface area of the sample. In this manner, portions of the sample can be analyzed by mass spectrometry separately without moving the sample or the array 300.

FIG. 4 illustrates a cross sectional view of an exemplary embodiment of a microplasma device 400 in relation to a sample 470 surface. The microplasma device 400 illustrated in FIG. 4 can be a stand alone device or represent a single device within an array as described above in FIGS. 2 and 3. The microplasma device 400 can comprise a first electrode 410 and a second electrode 420 separated by a dielectric 430. A first aperture 440 can traverse the thickness of the electrodes 410 and 420 and the dielectric 430. The aperture 440, electrodes 410 and 420 and dielectric 430 can be substantially similar to the corresponding elements described above with regard to FIGS. 1A and 1B.

The microplasma device 400 can further comprise a third electrode 450. The third electrode 450 can be substantially similar in dimension and composition to the second electrode 420. The third electrode 450 can be disposed substantially parallel to the second electrode 420. The third electrode 450 can be spaced apart from the electrode, preferably no further than 1 mm. The distance between the third electrode 450 and second electrode 420 can vary between embodiments and applications of the microplasma device 400. The third electrode 450 can be unexcited and maintained at a ground potential, or excited with a varying or constant potential.

The third electrode 450 can comprise a second aperture 451. The second aperture 451 can traverse the thickness of the third electrode. The second aperture 451 can be concentrically aligned with the first aperture 440 and similar or smaller in diameter to the first aperture 440.

The microplasma device 400 can be positioned over the surface of a sample 470. The sample 470 and/or microplasma device 400 can be positioned such that the second aperture 450 is directly above a target site 471 that is to be analyzed.

A gas mixture 480 can be injected through the first aperture 440. The gas mixture 480 is preferably composed of molecules that may be readily ionized to form a plasma. The mixture 480 can comprise different types of molecules or a single type of molecule or atom. In an exemplary embodiment, the mixture comprises neon and hydrogen. In other embodiments, the gas 480 may comprise neon or another noble gas alone, or a mixture such as air.

The field generated by the excitation of electrodes **410** and **420** can partially ionize the gas mixture **480**. In an exemplary embodiment, the first electrode **410** can be an anode and the second electrode **420** can be a cathode. In other contemplated embodiments, the first electrode **410** can be a cathode and the second electrode **420** can be an anode, in this configuration the field generated within the aperture **440** can minimize the number of ionized particles passing through the aperture **440**, allowing primarily VUV photons to pass therethrough. As described above, in each of the exemplary embodiments, the excitation source can be a pulsed voltage. A pulsed voltage can result in an increase in the concentration of metastables and VUV photons produced, as well as reducing the increase in temperature of the plasma **481**. The gas mixture **480** forms a plasma **481** as it passes through the aperture **440**. The plasma **481** can comprise metastable particles, highly excited hydrogen atoms and molecules, high energy electrons, high energy photons, and other ions. A plasma effluent stream **482** can be ejected from the aperture **440** and continue to diffuse across the gap between the second electrode **420** and the third electrode **450**. The effluent stream **482** can comprise energetic electrons, VUV photons, metastable particles, ions, and neutral gas. Upon reaching the third electrode **450** and passing through the second aperture **451**, the effluent stream **482** can interact with the target site **471**. The interaction of the effluent stream **482** with the surface of sample **470** can be delimited by the diameter of the aperture **451**. The diameter of aperture **451** can be selected to correspond to the area of the surface of sample **470** that is desired to be analyzed. Accordingly, the diameter of aperture **451** can be different from the diameter of aperture **440**.

The interaction between the effluent stream **482** and the target site **471** can desorb and remove molecules from the sample **470**. The metastable molecules in the effluent stream **482** can transfer energy in collisions with the sample, breaking apart bonds between molecules of the sample, and between atoms and molecules on the sample. Further, the excited hydrogen molecules emit photons in the VUV wavelength also breaking apart bonds. The primary VUV photons assist in removing atoms and molecules from the surface. This process of desorption and removal from the surface of the target site **471** with the effluent stream **482** can be primarily nonthermal. In other embodiments, thermal desorption may be occurring in conjunction with nonthermal desorption. The combination of metastables, excited hydrogen molecules, electrons, photons, and ions in the effluent stream **482** can efficiently desorb molecules from the surface of the target site without thermal damage occurring to the remainder of the sample **470**.

The desorbed molecules from the target site **471** are ejected from the surface of the sample **470** and can form a plume **483** located directly above the target site **471**. As the desorbed sample molecules are ejected forming plume **483**, the molecules in the plume **483** can be ionized by the effluent stream **482**, which passes through the plume **483**. The effluent stream **482** can ionize the sample molecules in the plume **483** through one or more possible ionization channels. The metastable molecules in the effluent stream **482** can ionize the sample molecules in the plume **483** through penning ionization. Further, the excited hydrogen molecules can emit VUV photons, which photoionize the molecules. Additionally, proton transfer ionization can occur given the presence of water.

FIG. 5A illustrates a cross sectional view of an exemplary embodiment of a microplasma device **500** with a guide electrode. The microplasma device **500** illustrated in FIG. 5 can be a stand alone device or represent a single device within an array as described above in FIGS. 2 and 3. The microplasma

device **500** can comprise a first electrode **510** and a second electrode **520** separated by a dielectric **530**. A first aperture **540** can traverse the thickness of the electrodes **510** and **520** and the dielectric **530**. The device **500** can further comprise a third electrode **550** having a second aperture **551**. The apertures **540** and **551**, electrodes **510**, **520**, and **550**, and dielectric **530** can be substantially similar to the corresponding elements described above with regard to FIG. 4.

The microplasma device **500** can further comprise a fourth electrode **560**. The fourth electrode **560** can be disposed between the second electrode **520** and the third electrode **550**. The fourth electrode **560** is preferably substantially parallel to the second electrode **520** and third electrode **550** and spaced apart approximately 1 mm between the second **520** and third **550** electrodes.

The fourth electrode **560** can comprise a cylindrical wall **561** orthogonal to the surface of the fourth electrode **560**. The wall **561** can define a cylindrical conduit **562**. The conduit **562** can be substantially similar in diameter to the first aperture **540**. The conduit **562** can be concentrically aligned with the first aperture **540**.

A gas **580** can be injected through first aperture **540** to form a plasma **581**. This process is substantially similar to the plasma formation process described above. The effluent stream **582** can continue through the conduit **562** upon exiting the first aperture **540**. The fourth electrode **560** can be excited to generate an electric and magnetic field within the conduit **562**. The field within the conduit **562** can serve multiple functions. First, the field can block the passage of ions within the effluent plume **582**. Second, the field can focus the effluent stream **582** and minimize the spreading of charged particles exiting the first aperture **540**. This can concentrate the stream **582** and increase the portion of the effluent stream **582** that passes through the second aperture **552** and interacts with the target site **571** of the surface of the sample **570**. This can also be used to remove cations and focus a beam of electrons and negative ions from the effluent stream **582**. This would allow mass spectrometry of negative ions from the sample. Absent the fourth electrode **560**, the effluent stream **582** may spread to a diameter greater than the diameter of the second aperture **551**, consequently not all the charged particles in the plume **581** may reach the target site **571**. The effluent stream **582** can interact with the target site **571** to form a plume **583** in substantially the same manner as described above.

FIG. 5B illustrates a cross sectional view of an exemplary embodiment of a microplasma device **500** with a solenoid **565**. In other contemplated embodiments, the solenoid can encompass the microplasma device **550** and the sample **570**. The microplasma device **500** can be substantially similar to the device illustrated in FIG. 5A. In the embodiment illustrated in FIG. 5B, however, the fourth electrode **560** can be replaced with a solenoid **565**. The solenoid **565** can be disposed proximate the second electrode **520**. The solenoid **565** can define a solenoid aperture **566**. The solenoid aperture **566** can be substantially equal in diameter to and concentrically aligned with the first aperture **540**.

The solenoid **565** can comprise helically stacked conductor coils, coplanar spiraling coils, or a combination of both. A DC voltage can be applied to the solenoid **565** to generate a magnetic field passing through the aperture **566**. The magnetic field can serve to focus the effluent stream **582** or to prevent charged particles from passing through the aperture **566**. In this manner, the solenoid **565** can serve as either a focusing lens or a filter. In other contemplated embodiments, the solenoid **565** can serve as both a lens and a filter.

The embodiments of the microplasma device **400** and **500** can be employed as an ion source for a mass spectrometer.

The embodiments of the microplasma device **400** and **500** desorb molecules from a sample surface and ionize the molecules in the resulting plume. In these embodiments, the devices **400** and **500** are not sealed off from ambient air. These embodiments rely upon extraction and transport of the ionized sample molecules from the surface of a target site to a mass analyzer of a mass spectrometer. The following exemplary embodiment discloses a microplasma device that is sealed off from ambient air and comprises channels for directing flow of gasses.

FIG. 6 illustrates a cross sectional view of an exemplary embodiment of a sealed microplasma device **600**. The microplasma device **600** illustrated in FIG. 6 can be a stand alone device or represent a single device within an array as described above in FIGS. 2 and 3. The microplasma device **600** can comprise a first electrode **610** and a second electrode **620** separated by a dielectric **630**. A first aperture **640** can traverse the thickness of the electrodes **610** and **620** and the dielectric **630**. The device **600** can further comprise a third electrode **650** having a second aperture **651**. The apertures **640** and **651**, electrodes **610**, **620**, and **650**, and dielectric **630** can be substantially similar to the corresponding elements described above with regard to FIG. 4. In another contemplated embodiment, the device **600** can comprise a fourth electrode substantially similar to the fourth electrode described above with regard to FIG. 5.

The device **600** can further comprise an enclosure **690** substantially surrounding the outer portion of the first electrode **610**. The enclosure **690** can be dome shaped, square, or another suitable configuration. The enclosure **690** can define a chamber **692**. A gas mixture **680** can be injected through a first port **691** in the enclosure **690** into the chamber **692**. The gas mixture **680** can be substantially similar to the gas mixtures described above. The gas **680** can flow from the chamber **692** through the first aperture **640**. The injection of the gas **680** into the chamber **692** and resulting passage through first aperture **640** can be pulsed.

As the first and second electrodes **610** and **620** are excited, the gas **680** can form a plasma **681**. The plasma **681** can flow from the first aperture **640** through the second aperture **651** where it can interact with the target site **671** on the surface of sample **670**. The effluent stream **682** can desorb molecules from the surface of sample **670** at the target site **671** and ionize the molecules after they have broken away from the surface. In contemplated embodiments, the effluent stream **682** can ionize molecules from the target site **671** as the molecules are being desorbed.

The device **600** can further comprise a tube **693** disposed parallel to and between the second **620** and third **650** electrodes. The tube **693** can traverse the width of the device **600**. The tube **693** can comprise portals **696** aligned with the first aperture **640** and second aperture **651**. The portals **696** can allow the effluent stream **682** to pass through the tube **693** as the effluent stream **682** flows from the first aperture **640** to the second aperture **651**.

The tube **693** can further comprise an inlet port **694** and an outlet port **695**. A transport gas **682** can be injected through the inlet port **694** and flow into the tube **693**. As the transport gas **682** flows through the tube **693** it can direct the ionized fragments of the sample **670** above the target site **671** toward the outlet port **695**. The sample gas **683** flowing toward the outlet port **695** can be a mixture of the transport gas **682** and ionized sample fragments. The outlet port **695** can lead to the mass analyzer of a mass spectrometer.

The embodiment described above in relation to FIG. 6 disclose a device **600** wherein the gas, ionizing plasma effluent stream, and ionized sample molecules are isolated from

the ambient atmosphere. This embodiment enables transporting ionized sample fragments to a mass analyzer without contamination from, for example, the ambient air. This improves the accuracy of the sample analysis.

In embodiments wherein the device **600** comprises an array of microplasma devices, as described in FIGS. 2 and 3, the enclosure **690** can surround all of the apertures in the device. In other contemplated embodiments, each aperture can have a separate enclosure such that gas flow through each aperture can be independently regulated.

FIG. 6B illustrates an exploded perspective view of an exemplary embodiment of a sealed microplasma device with a gas transport channel. The device **600** is substantially similar to the embodiment illustrated in FIG. 6A. The enclosure **690** is not pictured to simplify illustration. The present embodiment differs from that of FIG. 6A in that the tube **693** is replaced with a channel element **660**.

The channel element **660** can be disposed between the second **620** and third **650** electrodes. The element **660** can abut against both the electrode **620** and **650**. The element **660** can comprise a channel **661** carved or other with formed along the entire width of the element **660**. When the element **660** is proximate the second electrode **620**, the channel **661** can define a conduit for conveying gas. The element **660** can comprise a channel aperture **662**, substantially equal in diameter and concentrically aligned with the first aperture **640**. The effluent stream **682** can pass through the channel aperture **662** and continue to the second aperture **651**, where it can interact with the target site **671** of sample **670** as described above. The plume **683** resulting can extend into the channel **661** above the aperture **662**.

A transport or sweeper gas **684** can be injected into the channel **661** and carry matter from the plume **683** to a mass analyzer. The excitation of the electrode **610** and **620** can be pulsed as described above. Similarly, the injection of gas **684** can be pulsed and synchronized with excitation of the electrodes **610** and **620** to avoid diverting the effluent stream **682** to the mass analyzer, preventing it from reaching the target site **671**. In other contemplated embodiments, the enclosure **690** can be omitted. In additional contemplated embodiments, the enclosure **690** can be incorporated in substantially similar form to all of the embodiments of the microplasma device(s) described herein.

FIG. 7 illustrates a cross sectional view of an exemplary embodiment of a microplasma device **700** for use with a microfluidic sample. The microplasma device **700** illustrated in FIG. 7 can be a stand alone device or represent a single device within an array as described above in FIGS. 2 and 3. The microplasma device **700** can comprise a first electrode **710** and a second electrode **720** separated by a dielectric **730**. A first aperture **740** can traverse the thickness of the electrodes **710** and **720** and the dielectric **730**. The device **700** can further comprise a third electrode **750** having a second aperture **751**. The apertures **740** and **751**, electrodes **710**, **720**, and **750**, and dielectric **730** can be substantially similar to the corresponding elements described above with regard to FIG. 4. In another contemplated embodiment, the device **700** can comprise a fourth electrode substantially similar to the fourth electrode described above with regard to FIG. 5.

The device **700** can further comprise a tube **790**. The tube **790** can be a tube defining a conduit **791**. The diameter of the conduit is preferably less than or equal to 1 mm. The channel can further comprise a portal **794** forming an opening between the second aperture **751** and the conduit **791**. The portal **794** can be concentrically aligned with and approximately equal in diameter to the second aperture **751**.

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The tube **790** can further comprise an inlet port **792** and an outlet port **793**. A sample can be injected through the inlet port **792** into the conduit **791**. The sample can be a microfluidic specimen. For example, the sample **770** can be, but is not limited to, a cell, spore, or other biological entity. In other contemplated embodiments, the sample **770** can be a different micro scale specimen. The tube **790** can receive other fluid or fluidized samples as well. The diameter of the channel can be varied depending on the size and parameters of the sample to be analyzed. The sample **770** can flow through the conduit **791** toward the outlet port **793**. As the sample **770** passes underneath the portal **794** it can be exposed to the effluent stream **782**. The effluent stream **782** can fragment and ionize the surface of the sample proximate the portal **794** in substantially the same manner as described above. The ionized fragments of the sample **770** can be directed to a mass analyzer of a mass spectrometer. The sample **770** can continue along the conduit **791** and exit the tube **790** through the outlet port **793**.

In other contemplated embodiments, a tube or channel element could be disposed between the second **720** and third electrodes **750** as described above with regard to FIGS. **6A** and **6B**. Further, tube **790** can be replaced by a channel element substantially similar to channel element **660** to transport a microfluidic sample.

FIG. **8A** illustrates a cross sectional view of an exemplary embodiment of a mass spectrometry analysis system **800**. The system **800** can comprise a microplasma device **801**. The microplasma device **801** illustrated in FIG. **8** can be a stand alone device or represent a single device within an array as described above in FIGS. **2** and **3**. The microplasma device **801** can comprise a first electrode **810** and a second electrode **820** separated by a dielectric **830**. A first aperture **840** can traverse the thickness of the electrodes **810** and **820** and the dielectric **830**. The device **801** can further comprise a third electrode **850** having a second aperture **851**. The apertures **840** and **851**, electrodes **810**, **820**, and **850**, and dielectric **830** can be substantially similar to the corresponding elements described above with regard to FIG. **4**. In another contemplated embodiment, the device **801** can comprise a fourth electrode substantially similar to the fourth electrode described above with regard to FIG. **5**.

The system **800** can further comprise a microscope **890**. The microscope **890** can be an optical microscope. For example, the microscope **890** can be a Raman microscope, a fluorescence microscope, and both near-field and far-field optical imaging systems. In other contemplated embodiments, the microscope **890** may be a microscope other than an optical microscope. In other contemplated embodiments, the microscope **890** can be replaced with another suitable imaging device.

The microscope **890** can be disposed inline with the device **801**. In particular, the line of sight of the microscope can be parallel to the propagation axis of the effluent stream **882**. In other contemplated embodiments, the line of sight of the microscope **890** can be offset from the axis of the effluent stream **882**.

In an exemplary embodiment, the microscope **890** can be positioned to view a sample **870** from underneath. The sample **870** can be a specimen on a slide. In other embodiments, the sample can be any specimen suitable for imaging by a microscope. The device **801** can be positioned above the sample **870** and microscope **890**. The microscope **890** can be used to locate the position of a target portion **871** or area within the sample **870**. For example, the microscope **890** can be used to locate a particular cell within the sample **870**. The target portion **871** may be anywhere within the sample **870**. Because the sample **870** can be substantially larger than the

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aperture **851**, the target portion **871** is not likely to be initially located directly underneath the aperture **851**. Consequently, the target portion **871** might not be immediately ionized by the effluent stream **882**.

After locating the target portion **871** within the sample **870**, the microscope **890** and/or sample **870** can be repositioned such that the target portion **871** rests directly below the aperture **851**. In this manner, a molecules at a particular target portion **871** can be desorbed and ionized by the effluent stream **882**. The system **800** can further comprise a mass analyzer and detector **895** having an inlet port **896**. The fragmented and ionized molecules from the target portion **871** of the sample **870** can be directed through the inlet port **896** for analysis. The optical analysis can also be performed simultaneously with the mass spectral imaging.

The embodiment described above of system **800** can incorporate various features of any of the previously described embodiments. For example, the device **801** can be sealed from ambient air, incorporating features of the embodiment illustrated in FIG. **6**. The device **800** can also incorporate a fourth electrode as illustrated in FIG. **5**. In other contemplated embodiments, the third electrode can be omitted. In further contemplated embodiments, a channel element substantially similar to element **660** can be disposed between the second **820** and third **850** electrodes to direct matter from the plume **883** to the mass analyzer **895**. Additionally, in contemplated embodiments, the sample **870** can be a microfluidic sample within a tube or channel element substantially similar to those described above.

FIG. **8B** illustrates a cross sectional view of alternative orientation of an exemplary embodiment of a mass spectrometry analysis system **800**. The system **800** is substantially identical to the system described above in FIG. **8A**. In this embodiment, however, the microscope **890** can be disposed above the device **801**, which can be sandwiched between the microscope **890** and a sample **870**. The line of sight of the microscope **890** can pass directly through the first aperture **840** and second aperture **851**, allowing a user to see the target sight **871** on the sample **871**. If the sample **870** is a cell culture and the target site **871** is a particular cell, this orientation allows a user to see the side of the cell that will be actually analyzed, rather than the bottom of said cell as in the orientation of FIG. **8A**.

The embodiment variations described above with regard to FIG. **8A** can also be applied to the embodiment of FIG. **8B**. In particular, it is contemplated that a channel element substantially similar to element **660** can be disposed between the second **820** and third **850** electrodes to direct matter from the plume **883** to the mass analyzer **895**. Additionally, it is contemplated that sample **870** can be a microfluidic sample within a tube or channel element substantially similar to those described above.

FIG. **9A** illustrates a cross sectional view of an exemplary embodiment of a configuration for an imaging mass spectrometry system **900** comprising a microplasma ion source **901**. The mass spectral imaging system **900** can comprise an ion source **901**, a mass analyzer **990**, and a detector **991**. The ion source **901** can be a microplasma device in accordance with any of the embodiments described above.

In an exemplary embodiment, the ion source **901** can be a microplasma device comprising a first electrode **910**, a second electrode **920**, and a dielectric **930** disposed between the electrodes **910** and **920**. The ion source **901** can further comprise an aperture **940** traversing the thickness of the electrodes **910** and **920** and the dielectric **930**. The dimensions and function of the electrodes **910** and **920** and the dielectric **930** can be substantially similar to the corresponding ele-

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ments described in the embodiments above. The ion source 901 can comprise a single microplasma device or an array of such devices as illustrated in FIGS. 2 and 3.

The electrodes 910 and 920 are designed to generate electric and magnetic fields. In particular, the electrodes 910 and 920, can be excited by DC, radio-frequency, AC or a pulsed voltage to generate an electric and magnetic field within the aperture 940. A gas 980 can be directed to flow through the aperture 940 to form a plasma 981. The composition of the gas 980 can be substantially similar to the gas mixtures described in relation to the embodiments disclosed above.

The effluent stream 982 from the aperture 940 can desorb and ionize molecules at a target portion 971 of the surface of a sample 970 in substantially the same manner as described above. The neutral and ionized molecules in the plume 983 from the target portion 971 of the sample 970 can be directed around the sample 970, as shown by arrow 984, first to a mass analyzer 990 and then to a detector 991. The mass-to-charge ratio of the molecules passing through the mass analyzer 990 can be determined by the detector 991. This data can be analyzed to calculate the composition of the molecules.

In the above described embodiment of the mass spectrometry imaging system 900, the ion source 901 and mass analyzer 990 are arranged substantially inline. In particular, the sample 970 can be disposed directly between the ion source 901 and the mass analyzer 990. Various types of samples, however, may not allow for such an arrangement. In other contemplated embodiments, the ion source 910 and the mass analyzer 990 can be oriented orthogonally. FIG. 9B illustrates an exemplary embodiment of an orthogonal orientation of an imaging mass spectrometry system 900 comprising a microplasma ion source 901. In other contemplated embodiments, the ion source 910 and mass analyzer 990 can also be oriented at other angles depending upon the sample and particular implementation of the mass spectrometer 900. For example, the ion source 901 and mass analyzer 990 can both be disposed above the surface of the target portion 971 at 45 degree angles relative to the surface.

The embodiment described above of ion source 901 can incorporate various features of any of previously described embodiments. For example, the ion source 901 can be sealed from the ambient air, incorporating features of the embodiment illustrated in FIG. 6. Further, the ion source 901 can also incorporate a fourth electrode as illustrated in FIG. 5. Additionally, in other embodiments, the ion source 901 can include a third electrode as illustrated in FIG. 4.

Various exemplary embodiments have been disclosed above. It will be apparent to those skilled in the art that many modifications, additions, and deletions, especially in matters of shape, size, and arrangement of parts, can be made therein without substantially departing from the design function of the embodiments described herein. Therefore, other modifications or embodiments as may be suggested by the teachings herein are particularly reserved as they fall within the breadth and scope of the claims here appended.

The invention claimed is:

1. A system for chemically and spatially imaging a sample comprising:

- a ion source comprising a first electrode, a second electrode, a dielectric element disposed between the first and second electrodes, and a first aperture traversing the first electrode, second electrode, and dielectric element;
- a microfluidic mounting plane for incorporation of the ion-source into a translation scanning stage;
- a translation scanning stage for spatial imaging; and
- a spatial discrimination stage.

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2. The system of claim 1, the ion source transforming one or more gases passing through the first aperture into a plasma.

3. The system of claim 2, wherein the one or more gases comprises air, argon, helium and neon.

4. The system of claim 3, wherein the one or more gases further comprise hydrogen to produce high energy vacuum ultraviolet photons.

5. The system of claim 1, further comprising a power source coupled to the first electrode and the second electrode, the power source exciting the first electrode and second electrode to generate a field within the first aperture, the field partially ionizing a gas passing through the aperture to form a plasma.

6. The system of claim 5, wherein the power source is a DC power source, an AC power source, or a pulsed voltage power source.

7. The system of claim 1, further comprising a third electrode disposed parallel to the second electrode, the third electrode having a second aperture concentrically aligned with the first aperture.

8. The system of claim 7, further comprising a fourth electrode disposed parallel to the second electrode and located between the second and third electrodes, the fourth electrode defining a conduit concentrically aligned with the first aperture.

9. The system of claim 7, further comprising an enclosure surrounding a portion of the first electrode, the enclosure receiving the gas and direct the gas into the first aperture, the enclosure securing the first aperture from ambient conditions.

10. The system of claim 9, further comprising a channel disposed between the second and third electrodes, the channel having a first portal and a second portal, the first and second portal concentrically aligned with the first and second apertures, the channel directing a transport gas through a conduit defined by the channel past the first and second portals to the mass analyzer.

11. The system of claim 1, further comprising:

- a third electrode disposed parallel to the second electrode, the third electrode having a second aperture concentrically aligned with the first aperture; and
- a fourth electrode disposed parallel to the second electrode and between the second and third electrodes, the fourth electrode defining a cylindrical conduit concentrically aligned with the first aperture.

12. The system of claim 11, further comprising:

- an enclosure surrounding a portion of the first electrode, the enclosure adapted to receiving a gas and directing the gas into the first aperture, the enclosure securing the first aperture from ambient conditions; and
- a channel disposed between the second and third electrodes, the channel having a first portal and a second portal, the first and second portals concentrically aligned with the first and second apertures, the channel having an inlet for receiving a transport gas, the channel directing the transport gas through a conduit defined by the channel past the first and second portals to an outlet coupled to the mass analyzer.

13. The system of claim 1, wherein the ion-source is a non-thermal plasma.

14. The system of claim 13, wherein the non-thermal plasma ionization occurs under ambient temperature or pressure, or both.

15. The system of claim 13, wherein one or more components of the plasma escape a plasma region of the plasma and ionize at least a portion of the sample.

16. The system of claim 1, further comprising a mass analyzer.

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17. The system of claim 1, further comprising a charged particle detector.

18. The system of claim 1, wherein the spatial discrimination stage is a mechanical scanning stage that translates one or more of the sample, the ion source, or a desorption mechanism.

19. The system of claim 1, wherein the spatial discrimination stage is a microscope.

20. The system of claim 1, further comprising an optical imaging stage.

21. The system of claim 1, wherein the ion source ionizes at least a portion of the sample directly.

22. The system of claim 1, wherein the ion source ionizes the sample indirectly.

23. A system for imaging a sample, the system comprising: 15  
an ion source ;

an array comprising:

a plurality of first front electrodes disposed in parallel on a first side of the array;

a plurality of first back electrodes disposed in parallel on a second side of the array;

a dielectric element disposed between the plurality of first front electrodes and first back electrodes; and

a plurality of apertures traversing the plurality of first front electrodes first back electrodes and dielectric element; 25

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wherein the plurality of first front electrodes are disposed orthogonally to the plurality of first back electrodes; and  
a mass analyzer.

24. The system of claim 23, further comprising a device for detecting charged particles.

25. The system of claim 23, further comprising a scanning stage for imaging.

26. The system of claim 25, wherein the scanning stage comprises a microscope for optically locating a target portion of the sample.

27. The system of claim 26, wherein the microscope spatially-resolves image data and the mass analyzer measures mass spectral data simultaneously.

28. The system of claim 23, further comprising a power source coupled to at least one of the plurality of first front electrodes and at least one of the plurality of first back electrodes to generate a non-thermal plasma within at least one of the plurality of apertures.

29. The system of claim 28, wherein the power source is a DC power source, an AC power source, or a pulsed voltage power source.

30. The system of claim 28, further comprising a solenoid for pulsed operation of the ion source.

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